

SLOVENSKI STANDARD oSIST prEN 62228-1:2017

01-september-2017

Integrirana vezja - Vrednotenje elektromagnetne združljivosti (EMC) oddajnikovsprejemnikov - 1. del: Splošni pogoji in definicije

Integrated Circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions

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Ta slovenski standard je istoveten z: prEN 62228-1:2017

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Integrated circuits. Microelectronics

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47A/1018/CDV

COMMITTEE DRAFT FOR VOTE (CDV)

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2017-07-07

CLOSING DATE FOR VOTING: 2017-09-29

SUPERSEDES DOCUMENTS:

47A/995/CD,47A/1013A/CC

IEC SC 47A : INTEGRATED CIRCUITS				
SECRETARIAT:	SECRETARY:			
Japan	Mr Yoshinori FUKUBA			
OF INTEREST TO THE FOLLOWING COMMITTEES:	PROPOSED HORIZONTAL STANDARD:			
	 Other TC/SCs are requested to indicate their interest, if any, in this CDV to the secretary. 			
FUNCTIONS CONCERNED:				
EMC ENVIRONMENT	QUALITY ASSURANCE SAFETY			
SUBMITTED FOR CENELEC PARALLEL VOTING	NOT SUBMITTED FOR CENELEC PARALLEL VOTING			
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 Attention IEC-CENELEC parallel voting 				
 The attention of IEC National Committees, members of CENELEC, is drawn to the fact that this Committee Draft for Vote (CDV) is submitted for parallel voting. 	nt Preview			
The OFNELEO members are invited to us	<u> 62228-1:2018</u>			
 The CENELEC members are invited to vote through the CENELEC online voting system. 	8c9-4b2c-9802-4d55cbddc400/sist-en-iec-62228-1-2			

- This document is still under study and subject to change. It should not be used for reference purposes.

- Recipients of this document are invited to submit, with their comments, notification of any relevant patent rights of which they are aware and to provide supporting documentation.

TITLE:

Integrated circuits - EMC evaluation of transceivers - Part 1: General conditions and definitions

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29	INTERNATIONAL ELECTROTECHNICAL COMMISSION							
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32) CIRCUITS –					
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37		FORE	WORD					
38 39 40 41 42 43 44 45 46 47	 The International Electron all national electrotechninternational co-operation this end and in addition Technical Reports, Pub Publication(s)"). Their pro- in the subject dealt with governmental organization with the International O agreement between the top 	technical Commission (IEC) in nical committees (IEC Nation on all questions concerning to other activities, IEC pub- dicly Available Specification eparation is entrusted to tech h may participate in this porsons liaising with the IEC also rganization for Standardization wo organizations.	s a worldwide organization fo onal Committees). The ob- standardization in the electr lishes International Standard (PAS) and Guides (her nical committees; any IEC N preparatory work. Internation participate in this preparation (ISO) in accordance with	or standardization comprising ject of IEC is to promote rical and electronic fields. To ds, Technical Specifications, eafter referred to as "IEC ational Committee interested hal, governmental and non- on. IEC collaborates closely th conditions determined by				
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72 73	International Standard IEC 62228-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.							
74	The text of this standard is based on the following documents:							
		FDIS	Report on voting					
		47A/XX/FDIS	47A/XX/RVD					

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Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62228 series, published, in development or planned under the general title *Integrated circuits – EMC Evaluation of transceivers*, can be found below.

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- 81 Part 1: General conditions and definitions
- 82 Part 2: LIN transceivers
- 83 Part 3: CAN transceivers
- 84 Part 4: FlexRay transceivers
- 85 Part 5: Ethernet transceivers
- 86 Part 6: PSI5 transceivers
- 87 Part 7: CXPI transceivers
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The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "http://webstore.iec.ch" in the data related to the specific publication. At this date, the publication will be

- reconfirmed,
- withdrawn,
- replaced by a revised edition, or
- amended. amended.
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Document Preview

99	The National Committees are requested to note that for this publication the stability date	
100	is 2021 <u>SIST EN IEC 62228-1:2018</u>	
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101	THIS TEXT IS INCLUDED FOR THE INFORMATION OF THE NATIONAL COMMITTEES AND WILL BE	
102	DELETED AT THE PUBLICATION STAGE.	

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